

NOTICE - WHEN GOVERNMENT DRAWINGS, SPECIFICATIONS, OR OTHER DATA ARE USED FOR ANY PURPOSE OTHER THAN IN CONNECTION WITH A DEFINITELY RELATED GOVERNMENT PROCUREMENT OPERATION, THE UNITED STATES GOVERNMENT THEREBY INCURS NO RESPONSIBILITY FOR ANY OBLIGATION WHATSOEVER, AND THE FACT THAT THE GOVERNMENT MAY HAVE FORMULATED, FURNISHED, OR IN ANY WAY SUPPLIED THE SAID DRAWINGS, SPECIFICATIONS OR OTHER DATA IS NOT TO BE REGARDED BY IMPLICATION OR OTHERWISE AS IN ANY MANNER LICENSING THE HOLDER OR ANY OTHER PERSON OR CORPORATION, OR CONVEYING ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE, OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO.

B 01E9001

REVISIONS			
SYM	DESCRIPTION	DATE	APPROVAL
A	UPGRADED TO CLASS A WITH CHANGE PER TDRR 17369		<i>[Signature]</i>
B	REVISED PER TDRR 20618	27-6-51	<i>[Signature]</i>

REQUIREMENTS:

1. GENERAL:

- A. INTERPRET DRAWING IN ACCORDANCE WITH STANDARDS PRESCRIBED BY MIL-D-70327.
- B. UNITS SHALL MEET THE REQUIREMENTS OF MIL-S-19500 EXCEPT AS, AND IN ADDITION TO THE REQUIREMENTS, SPECIFIED HEREIN.
- C. SUPPLIER SHALL CONFORM TO THE QUALITY ASSURANCE PROVISIONS CONTAINED IN ND 1015404, CLASS 2.
- D. UNITS SHALL BE CAPABLE OF MEETING THE QUALIFICATION REQUIREMENTS OF ND 1002051.
- E. MARKING:
 - (1) PARTS SHALL BE PERMANENTLY AND LEGIBLY MARKED, IN ACCORDANCE WITH ND 1002019, WITH THE NASA PART NUMBER (DRAWING NUMBER AND REVISION LETTER) OR AS MANY SIGNIFICANT DIGITS AS POSSIBLE (E.G. 6310). OTHER MARKING SUCH AS MANUFACTURER'S IDENTIFICATION AND TYPE NUMBER IS PERMISSIBLE.
- F. PREPARATION FOR DELIVERY SHALL BE IN ACCORDANCE WITH ND 1002215, CLASS I, CODE 2.
 - (1) MARKING OF SHIPPING CONTAINERS SHALL CONFORM TO THE MARKING OF UNIT AND INTERMEDIATE PACKAGES AND THE METHODS OF MARKING AS SPECIFIED IN ND 1002215.

2. ACCEPTANCE AND INSPECTION:

- A. MECHANICAL PROPERTIES:
 - (1) DIMENSIONS: AS DELINEATED HEREIN.
- B. SEAL TEST: THE UNITS SHALL BE SUBJECTED TO A HELIUM OR RADIFLO LEAK DETECTION TEST WITH A SENSITIVITY OF AT LEAST 1×10^{-8} CC/ATM/SEC AND A HOT GLYCERINE BUBBLE TEST FOR GROSS LEAKS. THE LEAK TEST SHALL BE PERFORMED IN ACCORDANCE WITH MIL-STD-202C METHOD 112. TEST CONDITION C SHALL BE USED FOR THE HELIUM OR RADIFLO TEST. TEST CONDITION A SHALL BE USED FOR THE GROSS LEAK TEST EXCEPT THAT GLYCERINE SHALL REPLACE THE MINERAL OIL. A LEAKAGE RATE OF 1×10^{-8} CC-ATM-SEC OR GREATER SHALL CONSTITUTE A FAILURE.

ELECTRICAL CHARACTERISTICS: PER TABLES I, II, AND III AS LISTED BELOW:

- (1) PRE-ELECTRICAL TEST PROCESSING: ON LOTS OF 500 OR LESS, THE TESTS OF TABLE I SHALL BE PERFORMED IN THE SEQUENCE INDICATED BEFORE THE TESTS OF TABLE II.
- (2) ELECTRICAL TESTING: THE TESTS LISTED IN TABLE II SHALL BE PERFORMED AS LISTED BELOW:

- COLLECTOR CUTOFF CURRENT
- COLLECTOR-BASE BREAKDOWN VOLTAGE
- EMITTER-BASE BREAKDOWN VOLTAGE
- EMITTER-BASE REVERSE CURRENT
- COLLECTOR-EMITTER SUSTAINING VOLTAGE
- COLLECTOR-EMITTER CURRENT
- COLLECTOR-EMITTER THRESHOLD CURRENT
- DIRECT CURRENT GAIN
- BASE-EMITTER SATURATION VOLTAGE
- COLLECTOR-EMITTER SATURATION VOLTAGE
- COLLECTOR CAPACITANCE
- TURN-ON AND TURN-OFF TIME

PROCURE ONLY FROM APPROVED SOURCES LISTED IN ND 1002034 FOR THIS DRAWING.

- (3) QUALITY DEMONSTRATION TESTING: PER TABLE III ON LOTS MORE THAN 500 UNITS USING ACCEPTABLE UNITS FROM SUBGROUP 2 OF TABLE II FOR SUBGROUP 2, 3, AND 4 OF TABLE III. SUBGROUPS 1 AND 5 MAY USE ELECTRICAL REJECTS FROM THE SAME LOT.

D. VENDOR SUPPLIED DATA: EACH SHIPMENT OF PARTS SHALL BE ACCOMPANIED BY THE FOLLOWING DOCUMENTATION.

- (1) CERTIFICATE OF COMPLIANCE WITH LEAD MATERIAL REQUIREMENT.
- (2) CERTIFICATE OF COMPLIANCE WITH ND 1015404, CLASS 2.
- (3) CERTIFICATE OF COMPLIANCE WITH PARA.2 .C(1) OR 2.C(3). UNITS USED IN QUALITY DEMONSTRATION TESTS OF TABLE III WILL NOT BE SHIPPED AS PART OF THE DELIVERY SCHEDULE BUT WILL BE FORWARDED UNDER SEPARATE COVER WITH TEST DATA FOR EACH LOT SHIPMENT.

3. DESIGN:

- A. STORAGE LIFE: INDEFINITE WHEN STORED AT TEMPERATURES BETWEEN -65°C AND +150°C.
- B. ABSOLUTE MAXIMUM RATINGS AT 25°C AMBIENT.
 - (1) COLLECTOR-EMITTER VOLTAGE (V_{CE0}): 40 VDC
 - (2) COLLECTOR-BASE VOLTAGE (V_{CB0}): 60 VDC
 - (3) EMITTER-BASE VOLTAGE (V_{EB0}): 5 VDC
 - (4) COLLECTOR CURRENT (I_C): 600 MILLIAMPERES
 - (5) THERMAL RESISTANCE, JUNCTION-CASE (θ_{JC}): 50°C/WATT
 - (6) THERMAL RESISTANCE, JUNCTION-AMBIENT (θ_{JA}): 350°C/WATT
 - (7) TEMPERATURE RANGE, JUNCTION, OPERATING: -65°C TO +150°C.
 - (8) TEMPERATURE RANGE, STORAGE: -65°C TO +150°C

C. CONSTRUCTION:

- (1) SEMICONDUCTOR: SILICON PLANAR EPITAXIAL PNP
- (2) CASE: METAL CAN AND METAL HEADER HERMETICALLY SEALED (JEDEC TO-18)
- (3) COLLECTOR SHALL BE ELECTRICALLY CONNECTED TO THE CASE INTERNALLY.
- (4) LEAD MATERIAL: WELDABLE, GOLD PLATED, ANNEALED IRON-NICKEL-COBALT (KOVAR) ALLOY IN ACCORDANCE WITH ND 1015402.

QUALITY ASSURANCE REQUIREMENTS:

- (1) LOT DEFINITION: A GROUP OF PARTS IN A SINGLE PROCUREMENT SELECTED FROM A SINGLE CONTINUOUS PRODUCTION RUN USING LIKE MATERIALS WHICH ARE CONTROLLED USING A PROCESS WHICH IS THE SAME FROM THE BEGINNING TO THE END OF THE RUN.
- (2) INSPECTION CONDITIONS: UNLESS OTHERWISE SPECIFIED, ALL INSPECTIONS SHALL BE MADE AT AN AMBIENT TEMPERATURE OF $+25^\circ \pm 3^\circ\text{C}$.

		UNLESS OTHERWISE SPECIFIED DIMENSIONS ARE IN INCHES
		TOLERANCES ON
		FRACTIONS DECIMALS ANGLES
		$\pm \quad \pm \quad \pm$
		DO NOT SCALE THIS DRAWING
		MATERIAL
		SEE NOTE
		HEAT TREATMENT
		NONE
NEXT ASSY	USED ON	FINAL FINISH
		NONE
		APPLICATION

QTY REQD	PART OR IDENTIFYING NO.	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS			
	MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.	MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
	DWG. NO. CONTRACT DRAWN <i>[Signature]</i> DATES <i>[Signature]</i> CHECKED <i>[Signature]</i> USA	TRANSISTOR, SILICON, TYPE PNP, SWITCHING SPECIFICATION CONTROL DRAWING	
	APPROVAL <i>[Signature]</i> APPROVAL <i>[Signature]</i>	CODE IDENT NO. 80230 SIZE C	NASA DRAWING NO. 1006310
	NASA APPROVAL <i>[Signature]</i> MIT APPROVAL <i>[Signature]</i> MIT APPROVAL <i>[Signature]</i>	SCALE NONE WT	SHEET 1 OF 4

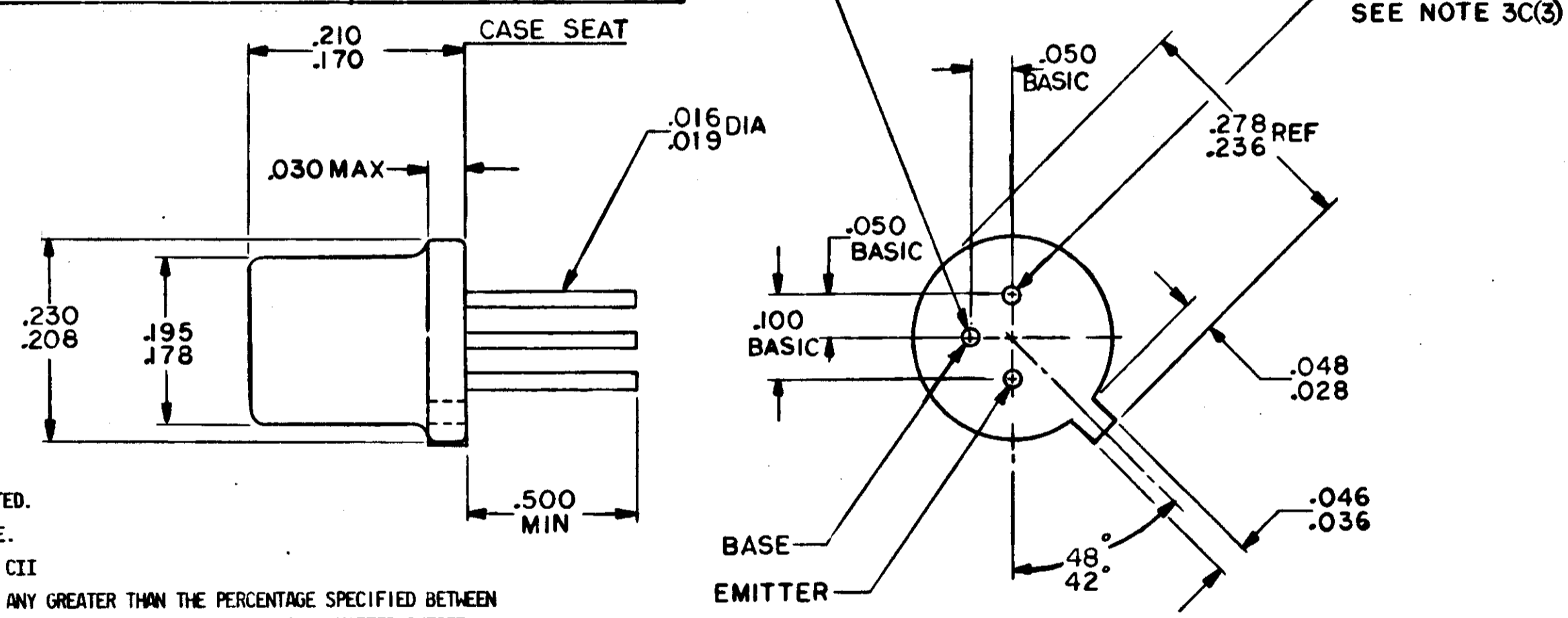
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B 01E9001

REVISIONS			
SYM	DESCRIPTION	DATE	APPROVAL
A	UPGRADED TO CLASS A WITH CHANGE PER TDRR 17369	11/26/65	WJK
B	REVISED PER TDRR 20618	7/27/65	WJK

TABLE I
PRE-ELECTRICAL TEST PROCESSING

TEST	MIL-STD-750 TEST CONDITIONS	LOT	
		1 TO 500	OVER 500
THERMAL SHOCK*	METHOD 1056, CONDITION B (+150°C TO -65°C, 3 CYCLES)	100%	NO REQUIREMENT
STORAGE LIFE* (HIGH TEMPERATURE STABILIZATION)	METHOD 1031, T _{stg} = 150° ± 5°C, 72 ⁺⁸ ₋₄ HOURS		
CONSTANT ACCELERATION*	METHOD 2006 (20,000 G) Y, AXIS		
POWER, BURN-IN*	METHOD 1026 P = 350 MILLIWATTS V _{CE} = -20.0 VOLTS MINIMUM T _A = +22°C MIN IN FREE AMBIENT AIR t = 168 ⁺¹² ₋₆ HOURS		
SEAL TEST*	MIL-STD-202C, METHOD 112, CONDITION C 10 ⁻⁸ ATM CC/SEC MAX = ACCEPTANCE		



- * TESTS TO BE PERFORMED IN ORDER INDICATED.
- ** PULSE < 300 U SECS AT < 2% DUTY CYCLE.
- *** LTPD OR PER MIL-S-19500D, TABLE CI OR CII
- **** THE PARAMETER MEASURED MAY NOT CHANGE ANY GREATER THAN THE PERCENTAGE SPECIFIED BETWEEN THE INITIAL VALUE AND THE END OF TEST VALUE. VALUES OF COLLECTOR AND EMITTER CUTOFF CURRENTS LESS THAN 10 NANOAMPERES MAY BE CONSIDERED TO BE 10 NANOAMPERES FOR CALCULATING PERCENTAGE CHANGE.
- CURRENTS TO WITHIN ± 10%.

MASTER

QTY REQD	PART OR IDENTIFYING NO.	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS			
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
DRAWN <i>D. Monaghan</i> DATE 10 DEC 64 CHECKED <i>R.T. Drossick</i> 10 DEC 64		TRANSISTOR, SILICON, TYPE PNP, SWITCHING SPECIFICATION CONTROL DRAWING	
APPROVAL <i>Edson C. Hall</i> 22 Jan 65			
HEAT TREATMENT NONE		CODE IDENT NO. 80230	NASA DRAWING NO. 1006310
FINAL FINISH NONE		SCALE NONE	WT
APPLICATION		SHEET 2 OF 4	

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2

1 15737

4

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2

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B 1006310

REVISIONS			
SYM	DESCRIPTION	DATE	APPROVAL
-	INITIAL RELEASE CLASS B		
A	UPGRADED TO CLASS A WITH CHANGE PER TDRR 17369	7/16/65	W.H.
B	REVISED PER TDRR 20618	7/16/65	W.H.

TABLE II

ACCEPTANCE INSPECTION							
TEST	SYMBOL	MIL-STD-750 TEST CONDITIONS	LIMIT		UNITS	LOT	
			MIN	MAX		1 TO 500	OVER 500
SUBGROUP 1							
VISUAL AND MECHANICAL EXAMINATION		METHOD 2071 (SEE NOTE 2 A (3))				LTPD*** = 10 MAX ACC NO. = 3	LTPD*** = 10 MAX ACC NO. = 3
SUBGROUP 2							
COLLECTOR CUTOFF CURRENT	ICBO	V _{CB} = -50 V; I _E = 0		10	NA	100%	LTPD*** = 2 (COMBINED) MAX ACC NO. = 3
COLLECTOR CUTOFF CURRENT 150°C	ICBO	V _{CB} = -50 V; I _E = 0		10	uA		
COLLECTOR-BASE BREAKDOWN VOLTAGE	BV _{CB0}	I _C = -10 uA; I _E = 0	60		V		
EMITTER-BASE REVERSE CURRENT	I _{EBO}	V _{EB} = -3 V; I _C = 0		0.1	uA		
EMITTER-BASE BREAKDOWN VOLTAGE	BV _{EB0}	I _E = -10 uA; I _C = 0	5		V		
COLLECTOR-EMITTER SUSTAINING VOLTAGE**	V _{CEO SUST}	I _C = -10 mA PULSED I _B = 0	60				
COLLECTOR-EMITTER CURRENT RES. RETURN	ICER	V _{CE} = -20 V; R _{BE} = 100 K		10	uA		
COLLECTOR-EMITTER THRESHOLD CURRENT	ICES	V _{BE} = -0; V _{CE} = -50 V		10	NA		
DC CURRENT GAIN**	h _{FE}	I _C = -150 mA; V _{CE} = -10 V	80	240			
DC CURRENT GAIN**	h _{FE}	I _C = -10 mA; V _{CE} = -10 V	100				
DC CURRENT GAIN	h _{FE}	I _C = -1 mA; V _{CE} = -10 V	100				
DC CURRENT GAIN**	h _{FE}	I _C = -500 mA; V _{CE} = -10 V	30				
BASE-EMITTER SATURATION VOLTAGE**	V _{BE(sat)}	I _C = -50 mA; I _B = -2.5 mA	0.7	-1.0	V		
COLLECTOR-EMITTER SATURATION VOLTAGE**	V _{CE(sat)}	I _C = -50 mA; I _B = -2.5 mA		0.25	V		
COLLECTOR-EMITTER SATURATION VOLTAGE**	V _{CE(sat)}	I _C = -150 mA; I _B = -15 mA		0.4	V		
COLLECTOR CAPACITANCE	C _{ob}	V _{CB} = -10 V; I _E = 0; F = 0.14 mc		8	PF		
TURN ON TIME	t _{on}	I _{B1} ≈ 30 mA; I _C ≈ 300 mA t _w > 400 nsec 2% DUTY CYCLE		40	NSEC	LTPD*** = 5 MAX ACC = 0	LTPD*** = 5 MAX ACC = 0
TURN OFF TIME	t _{off}	I _{B1} = I _{B2} ≈ 30 mA; I _C ≈ 300 mA t _w > 400 nsec 2% DUTY CYCLE		100	NSEC		

PRINTED

QTY REQD	PART OR IDENTIFYING NO.	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS			
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
DRAWN <i>D. Thompson</i> DATE <i>DEC 65</i>		TRANSISTOR, SILICON, TYPE PNP, SWITCHING SPECIFICATION CONTROL DRAWING	
CHECKED <i>R.T. Dumas</i> DATE <i>12/22/65</i>			
APPROVAL <i>[Signature]</i>		CODE IDENT NO. 80230	SIZE C
APPROVAL <i>[Signature]</i>		NASA DRAWING NO. 1006310	
HEAT TREATMENT NONE		MIT APPROVAL <i>[Signature]</i>	SCALE NONE
FINAL FINISH NONE		MIT APPROVAL <i>[Signature]</i>	WT
NEXT ASSY	USED ON		SHEET 3 OF 4
APPLICATION			

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B 1006310

REVISIONS			
SYM	DESCRIPTION	DATE	APPROVAL
A	UPGRADED TO CLASS A WITH CHANGE PER TDRR 17369	1/27/65	WHL
B	REVISED PER TDRR 20618	2/27/65	WHL

TABLE III

QUALITY DEMONSTRATION TESTS			
TEST	MIL-STD-750 TEST CONDITIONS	LOT	
		1 TO 500	OVER 500
SUBGROUP 1 PHYSICAL DIMENSIONS	METHOD 2066	NO REQUIREMENTS	*** LTPD = 20 MAX ACC NO. = 1
SUBGROUP 2* THERMAL SHOCK	METHOD 1056.1 CONDITION B (+150°C TO -65°C, 5 CYCLES)		*** LTPD = 10 (COMBINED) MAX ACC NO. = 3
SEAL TEST			
SUBGROUP 3* STORAGE LIFE	METHOD 1031.1 Tstg = 150° ± 5°C, 1000 HOURS		*** LTPD = 10 (COMBINED) MAX ACC NO. = 3
SHOCK	METHOD 2016.1 1500 G, 0.5 MSEC 5 BLOWS EACH IN X1, Y1, Y2, Z1 DIRECTIONS, 20 BLOWS TOTAL		
VIBRATION VARIABLE FREQUENCY	METHOD 2056, 30 G FROM 5 TO 2000 CPS LIMITED TO 0.12 DOUBLE AMPLITUDE, 3 CYCLES, 15 MINUTES PER CYCLE MINIMUM.		
CONSTANT ACCELERATION	METHOD 2006, 20,000 G Y AXIS		
SUBGROUP 4 OPERATION LIFE	METHOD 1026.1 P = 350 MILLIWATTS V _{CE} = -20 VOLTS MINIMUM T _A = +22°C MIN IN FREE AMBIENT AIR t = 1000 HOURS	λ*** = 10 MAX ACC NO. = 3	
SUBGROUP 5* LEAD TENSION (COND A) LEAD FATIGUE (COND E)	METHOD 2036 4 POUND LOAD FOR 10 SECONDS 3 ARCS	*** LTPD = 20 (COMBINED) MAX ACC NO. = 3	

TABLE III (CONTINUED)

TEST	SYMBOL	TEST CONDITION	LIMIT
END POINTS FOR SUBGROUP 2			
COLLECTOR CUTOFF CURRENT	I _{CBO}	V _{CB} = -50V, I _C = 0	±50% ****
EMITTER-BASE REVERSE CURRENT	I _{EBO}	V _{EB} = -3V, I _C = 0	±50% ****
DC CURRENT GAIN	h _{FE}	V _{CE} = -10V, I _C = -10 mA	±10% ****
END POINTS FOR SUBGROUPS 3 AND 4			
COLLECTOR CUTOFF CURRENT	I _{CBO}	V _{CB} = -50V, I _E = 0	±100% ****
EMITTER-BASE REVERSE CURRENT	I _{EBO}	V _{EB} = -3V, I _C = 0	±100% ****
DC CURRENT GAIN	h _{FE}	V _{CE} = -10V, I _C = -10 mA	±20% ****

NOTED

QTY REQD	PART OR IDENTIFYING NO.	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS			
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
DRAWN <i>[Signature]</i> DATE 22 DEC 64 CHECKED <i>[Signature]</i> WSP		TRANSISTOR, SILICON, TYPE PNP, SWITCHING SPECIFICATION CONTROL DRAWING	
DO NOT SCALE THIS DRAWING MATERIAL SEE NOTE			
HEAT TREATMENT NONE		CODE IDENT NO. 80230	SIZE C
NEXT ASSY USED ON		NASA DRAWING NO. 1006310	
APPLICATION NONE		SCALE NONE	WT
		SHEET 4 OF 4	